



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:) Group Art Unit: 2857
Hidekazu MIYAIRI et al.) Examiner: J. West
Serial No. 10/808,499) <u>CERTIFICATE OF MAILING</u> I hereby certify that this correspondence is
Filed: March 25, 2004	being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on January 21, 2009. Mall
For: METHOD FOR TESTING	
SEMICONDUCTOR FILM,	
SEMICONDUCTOR DEVICE AND	
MANUFACTURING METHOD	
THEREOF	,

AMENDMENT

Honorable Commissioner of Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In response to the Official Action dated August 19, 2008, please consider the following amendments and remarks in connection with the above-identified application.

Amendments to the Claims are reflected in the listing of claims, which begins on page 2 of this paper.

Remarks begin on page 11 of this paper.